



34 V, Digital-Input Serializer for 5V Systems

FEATURES

- Eight Digital Sensor Inputs
 - High Input Voltage up to 34 V
 - Selectable Debounce Filters From 0 ms to 3 ms
 - Flexible Input Current-Limited 0.2 mA to 5.2 mA
 - Field Inputs Protected to 15-kV ESD
- Single 5V Supply
- Output Drivers for External Status LEDs
- Cascadable for More Inputs in Multiples of Eight

- SPI-Compatible Interface
- Over-Temperature Indicator

APPLICATIONS

- Industrial PCs
- Digital I/O Cards
- High Channel Count Digital Input Modules
- Decentralized I/O Modules

DESCRIPTION

The SN65HVS885 is an eight channel, digital-input serializer for high-channel density digital input modules in industrial and building automation. Operating from a 5V supply the device accepts field input voltages of up to 34V. In combination with galvanic isolators the device completes the interface between the high voltage signals on the field-side and the low-voltage signals on the controller side. Inputs signals are current limited and then validated by internal debounce filters.

With the addition of few external components, the input switching characteristic can be configured in accordance with IEC61131-2 for Type 1, 2 and 3 sensor switches.

Upon the application of load and clock signals, input data is latched in parallel into the shift register and afterwards clocked out serially.

Cascading of multiple devices is possible by connecting the serial output of the leading device with the serial input of the following device, enabling the design of high-channel count input modules. Multiple devices can be cascaded through a single serial port, reducing both the isolation channels and controller inputs required.

Input status can be visually indicated via constant current LED outputs. The current limit on the inputs is set by a single, external, precision resistor. An on-chip temperature sensor provides diagnostic information for graceful shutdown and system safety.

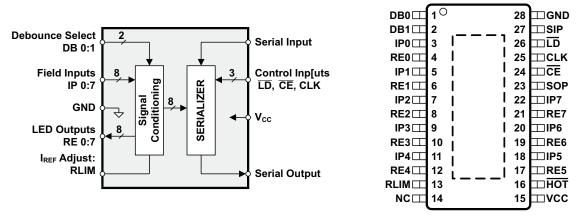
The SN65HVS885 is available in a 28-pin PWP PowerPAD™ package, allowing for efficient heat dissipation. The device is specified for operation at temperatures from –40°C to 125°C.

M

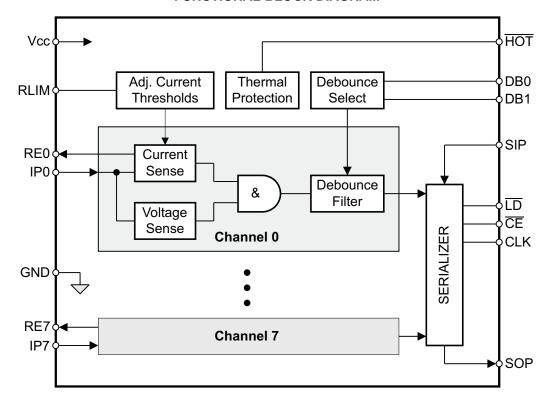
Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

PowerPAD is a trademark of Texas Instruments.





FUNCTIONAL BLOCK DIAGRAM





TERMINAL FUNCTIONS

TERM	INAL	DESCRIPTION
PIN NO.	NAME	DESCRIPTION
1, 2	DB0, DB1	Debounce select inputs
3, 5, 7, 9, 11, 18, 20, 22	IPx	Input Channel x
4, 6, 8, 10, 12, 17, 19, 21	REx	Return Path x (LED drive)
13	RLIM	Current Limiting Resistor
14	NC	Not Connected
15	V _{CC}	5 V Device Supply
16	HOT	Over-Temperature Flag
23	SOP	Serial Data Output
24	CE	Clock Enable Input
25	CLK	Serial Clock Input
26	LD	Load Pulse Input
27	SIP	Serial Data Input
28	GND	Device Ground

ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range (unless otherwise noted) (1)

				VALUE	UNIT
V_{CC}	Device power input		V _{CC}	-0.5 to 6	V
V_{IPx}	Field digital inputs Voltage at any logic input		IPx	-0.3 to 36	V
V_{ID}			DB0, DB1, CLK, SIP, $\overline{\text{CE}}$, $\overline{\text{LD}}$	-0.5 to 6	V
Io	Output current		HOT, SOP	±8	mA
		Human-Body Model (2)	All pins	±4	kV
.,	Floatrootatia diaabaraa	numan-body Moder	IPx	±15	KV
V _{ESD}	Electrostatic discharge	Charged-Device Model (3)	All pins	±1	kV
		Machine Model ⁽⁴⁾	All pins	±100	V
P _{TOT}	Continuous total power of	lissipation	See Thermal C	haracteristics table	
TJ	Junction temperature			170	°C

⁽¹⁾ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

THERMAL CHARACTERISTICS

	PARAMETER	TEST CONDITIO	MIN	TYP	MAX	UNIT	
θ_{JA}	Junction-to-air thermal resistance	High-K thermal resistance			35		°C/W
θ_{JB}	Junction-to-board thermal resistance				15		°C/W
θ_{JC}	Junction-to-case thermal resistance				4.27		°C/W
		$V_{CC} = 5 \text{ V}, R_{IN} = 0\Omega,$	IP0-IP7 = 34V				
_	Desires a server d'actación	$R_{LIM} = 25 \text{ k}\Omega$, RE0 – RE7 = GND,	IP0-IP7 = 30V			4400	14/
P_D	Device power dissipation	$f_{CLK} = 100 \text{ MHz}$	IP0-IP7 = 24V	1100		1100	mW
			IP0-IP7 = 12V				

RECOMMENDED OPERATING CONDITIONS

		MIN	TYP	MAX	UNIT
V _{CC}	Device supply voltage	4.5	5	5.5	V
V_{IPL}	Field input low-state input voltage	0		4	V
V_{IPH}	Field input high-state input voltage	5.5		34	V
V _{IL}	Logic low-state input voltage	0		0.8	V
V _{IH}	Logic high-state input voltage	2.0		5.5	V
R _{LIM}	Current limiter resistor	17	25	500	kΩ
f _{IP} ⁽¹⁾	Input data rate	0		1	Mbps
T _A	Device	-40		125	°C
TJ				150	°C

(1) Maximum data rate corresponds to 0 ms debounce time, (DB0 = open, DB1 = GND), and R_{IN} = 0 Ω

Submit Documentation Feedback

⁽²⁾ JEDEC Standard 22, Method A114-A.

⁽³⁾ JEDEC Standard 22, Method C101

⁽⁴⁾ JEDEC Standard 22, Method A115-A

ELECTRICAL CHARACTERISTICS

over full-range of recommended operating conditions (unless otherwise noted) all voltages measured against device ground, see Figure 9

	PARAMETER	TERMINAL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
FIELD IN	PUTS					,	
V _{TH-(IP)}	Low-level device input threshold voltage			4.0	4.3		V
V _{TH+(IP)}	High-level device input threshold voltage	IP0-IP7	$R_{LIM} = 25 \text{ k}\Omega$		5.2	5.5	V
V _{HYS(IP)}	Device input hysteresis				0.9		V
V _{TH-(IN)}	Low-level field input threshold voltage		4.5 V < V _{CC} < 5.5 V,	6	8.4		V
V _{TH+(IN)}	High-level field input threshold voltage	measured at field side of R _{IN}	$R_{IN} = 1.2 \text{ k}\Omega \pm 5\%,$		9.4	10	V
V _{HYS(IN)}	Field input hysteresis	I licia side of T(IN	$R_{LIM} = 25 \text{ k}\Omega, T_A \le 125^{\circ}\text{C}$		1		V
R _{IP}	Input resistance	IP0-IP7	$3 \text{ V} < \text{V}_{\text{IPx}} < 6 \text{ V},$ $R_{\text{LIM}} = 25 \text{ k}\Omega$	0.2	0.63	1.1	kΩ
I _{IP-LIM}	Input current limit	IP0-IP7	$R_{LIM} = 25 \text{ k}\Omega$	3.15	3.6	4	mA
			DB0 = open, DB1 = GND		0		
t _{DB}	Debounce times of input channels		DB0 = GND, DB1 = open		1		ms
			DB0 = DB1 = open		3		
I _{RE-on}	RE on-state current	RE0-RE7	$R_{LIM} = 25 \text{ k}\Omega, RE_X = GND$	2.8	3.15	3.5	mA
DEVICE S	SUPPLY						
I _{CC(VCC)}	Supply current	V _{CC}	IP0 to IP7 = 24V, RE _X = GND, All logic inputs open		6.5	10	mA
LOGIC IN	IPUTS AND OUTPUTS					,	
V _{OL}	Logic low-level output voltage	SOP. HOT	I _{OL} = 20 μA			0.4	V
V _{OH}	Logic high-level output voltage	50P, HOT	I _{OH} = -20 μA	4			V
I _{IL}	Logic input leakage current	DB0, DB1, SIP, LD, CE, CLK		-50		50	μΑ
T _{OVER}	Over-temperature indication				150		°C
T _{SHDN}	Shutdown temperature				170		°C

TIMING REQUIREMENTS

over operating free-air temperature range (unless otherwise noted)

	PARAMETER		MIN	TYP MAX	UNIT
t _{W1}	CLK pulse width	See Figure 6	4		ns
t _{W2}	LD pulse width	See Figure 4	6		ns
t _{SU1}	SIP to CLK setup time	See Figure 7	4		ns
t _{H1}	SIP to CLK hold time	See Figure 7	2		ns
t _{SU2}	Falling edge to rising edge (CE to CLK) setup time	See Figure 8	4		ns
t _{REC}	LD to CLK recovery time	See Figure 5	2		ns
f _{CLK}	Clock pulse frequency	See Figure 6	DC	100	MHz

SWITCHING CHARACTERISTICS

over operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH1} , t _{PHL1}	CLK to SOP	C _L = 15 pF, see Figure 6			10	ns
t _{PLH2} , t _{PHL2}	LD to SOP	C _L = 15 pF, see Figure 4			14	ns
t_r , t_f	Rise and fall times	C _L = 15 pF, see Figure 6			6	ns

Copyright © 2009, Texas Instruments Incorporated

TEXAS INSTRUMENTS

INPUT CHARACTERISTICS

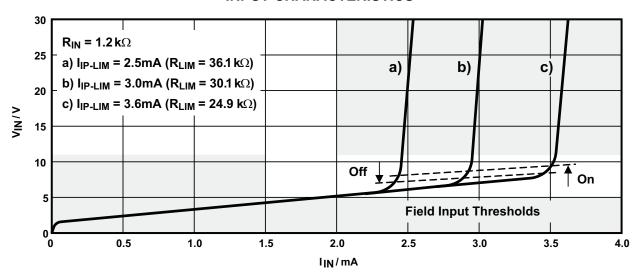


Figure 1. Typical Input Characteristics

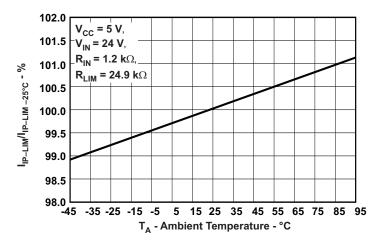


Figure 2. Typical Current Limiter Variation vs Ambient Temperature

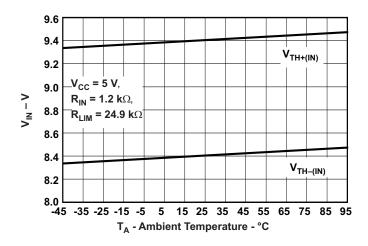
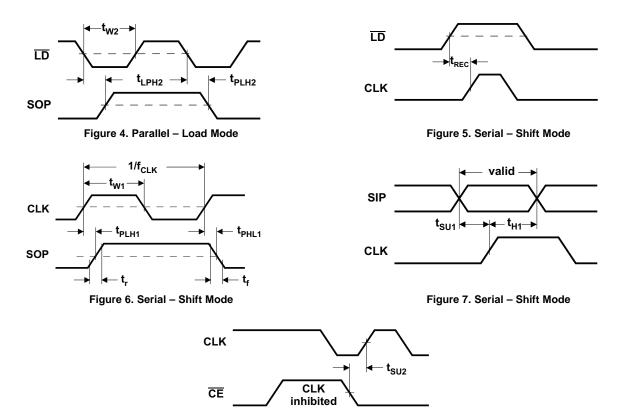


Figure 3. Typical Limiter Threshold Voltage Variation vs Ambient Temperature

PARAMETER MEASUREMENT INFORMATION

Waveforms

For the complete serial interface timing, refer to Figure 17.



Signal Conventions

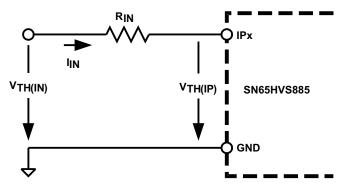


Figure 8. Serial – Shift Clock Inhibit Mode

Figure 9. On/Off Threshold Voltage Measurements



DEVICE INFORMATION

Digital Inputs

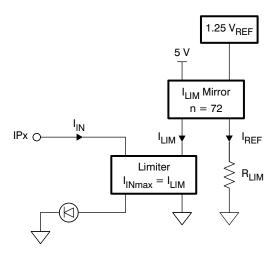


Figure 10. Digital Input Stage

Each digital input operates as a controlled current sink limiting the input current to a maximum value of I_{LIM} . The current limit is derived from the reference current via $I_{LIM} = n \times I_{REF}$, and I_{REF} is determined by $I_{REF} = V_{REF}/R_{LIM}$. Thus, changing the current limit requires the change of R_{LIM} to a different value via: $R_{LIM} = n \times V_{REF}/I_{LIM}$.

Inserting the actual values for n and V_{REF} gives: $R_{LIM} = 90 \text{ V} / I_{LIM}$.

While the device is specified for a current limit of **3.6 mA**, (via $R_{LIM} = 25 \text{ k}\Omega$), it is easy to lower the current limit to further reduce the power consumption. For example, for a current limit of **2.5 mA** simply calculate:

$$R_{LIM} = \frac{90 \text{ V}}{I_{LIM}} = \frac{90 \text{ V}}{2.5 \text{ mA}} = 36 \text{ k}\Omega$$

Debounce Filter

The HVS885 applies a simple analog/digital filtering technique to remove unintended signal transitions due to contact bounce or other mechanical effects. Any new input (either low or high) must be present for the duration of the selected debounce time to be latched into the shift register as a valid state.

The logic signal levels at the control inputs, DB0 and DB1 of the internal Debounce-Select logic determine the different debounce times listed in the following truth table.

Table 1. Debounce Times

DB1	DB0	FUNCTION
Open	Open	3 ms delay
Open	GND	1 ms delay
GND	Open	0 ms delay (Filter bypassed)
GND	GND	Reserved

Submit Documentation Feedback

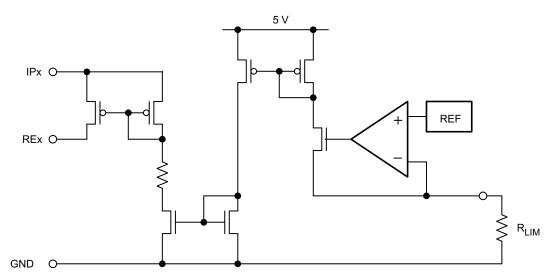


Figure 11. Equivalent Input Diagram

Shift Register

The conversion from parallel input to serial output data is performed by an eight-channel, parallel-in serial-out shift register. Parallel-in access is provided by the internal inputs, PIP0–PIP7, that are enabled by a low level at the load input (\overline{LD}) . When clocked, the latched input data shift towards the serial output (SOP). The shift register also provides a clock-enable function.

Clocking is accomplished by a low-to-high transition of the clock (CLK) input while \overline{LD} is held high and the clock enable (\overline{CE}) input is held low. Parallel loading is inhibited when \overline{LD} is held high. The parallel inputs to the register are enabled while \overline{LD} is low independently of the levels of the CLK, \overline{CE} , or serial (SIP) inputs.

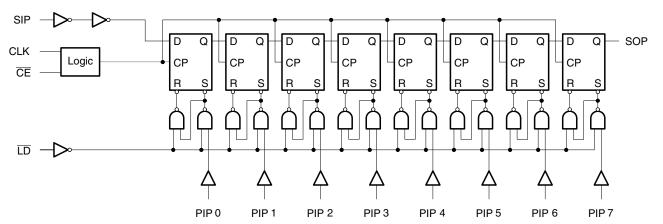


Figure 12. Shift Register Logic Structure



Table 2. Function Table

	INPUTS		FUNCTION			
LD	CLK	CE	FUNCTION			
L	Х	Х	Parallel load			
Н	Х	Н	No change			
Н	1	L	Shift ⁽¹⁾			

Shift = content of each internal register shifts towards serial outputs.
 Data at SIP is shifted into first register.

Temperature Sensor

An on-chip temperature sensor monitors the device temperature and signals a fault condition if the temperature exceeds a first trip point at 150°C by pulling the HOT output low. If the junction temperature continues to rise, passing a second trip point at 170 °C, all device outputs assume high impedance state.

A special condition occurs when the chip temperature exceeds the second temperature trip point due to an output short; the \overline{HOT} output buffer becomes high impedance, thus separating the buffer from the external circuitry. An internal $100\text{-}k\Omega$ pulldown resistor, connecting the \overline{HOT} -pin to ground, is used as a "cooling down" resistor, which continues to provide a logic low level to the external circuitry.

APPLICATION INFORMATION

System-Level EMC

The SN65HVS885 is designed to operate reliably in harsh industrial environments. At a system level, the device is tested according to several international electromagnetic compatibility (EMC) standards.

In addition to the device internal ESD structures, external protection circuitry shown in Figure 13, can be used to absorb as much energy from burst- and surge-transients as possible.

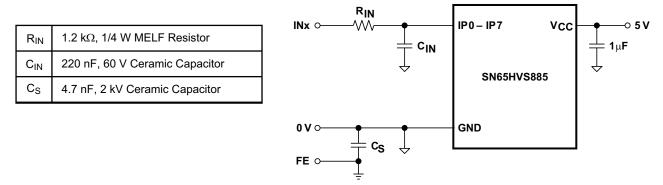


Figure 13. Typical EMC Protection Circuitry for Supply and Signal Inputs

Input Channel Switching Characteristics

The input stage of the HVS885 is so designed, that for an input resistor R_{IN} = 1.2 k Ω the trip point for signaling an ON-condition is at 9.4 V at 3.6 mA. This trip point satisfies the switching requirements of IEC61131-2 Type 1 and Type 3 switches.

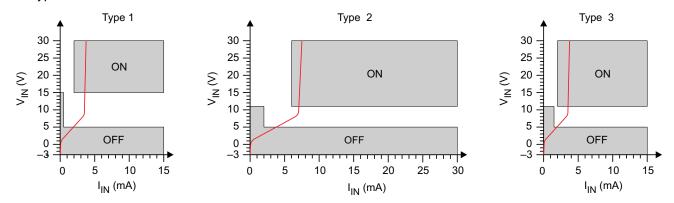


Figure 14. Switching Characteristics for IEC61131-2 Type 1, 2, and 3 Proximity Switches

For a Type 2 switch application, two inputs are connected in parallel. The current limiters then add to a total maximum current of 7.2 mA. While the return-path (RE-pin), of one input might be used to drive an indicator LED, the RE-pin of the other input channel should be connected to ground (GND).

Paralleling input channels reduces the number of available input channels from an octal Type 1 or Type 3 input to a quad Type 2 input device. Note, that in this configuration output data of an input channel is represented by two shift register bits.



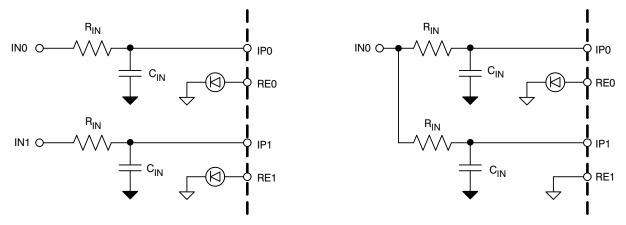


Figure 15. Paralleling Two Type 1 or Type 3 Inputs Into One Type 2 Input

Digital Interface Timing

The digital interface of the SN65HVS885 is SPI compatible and interfaces, isolated or non-isolated, to a wide variety of standard micro controllers.

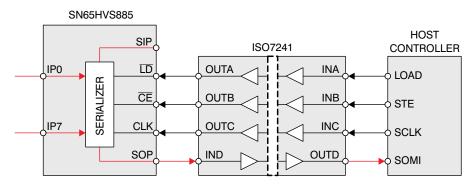


Figure 16. Simple Isolation of the Shift Register Interface

Upon a low-level at the load input, $\overline{\text{LD}}$, the information of the field inputs, IP0 to IP7 is latched into the shift register. Taking /LD high again blocks the parallel inputs of the shift register from the field inputs. A low-level at the clock-enable input, $\overline{\text{CE}}$, enables the clock signal, CLK, to serially shift the data to the serial output, SOP. Data is clocked at the rising edge of CLK. Thus after eight consecutive clock cycles all field input data have been clocked out of the shift register and the information of the serial input, SIP, appears at the serial output, SOP.

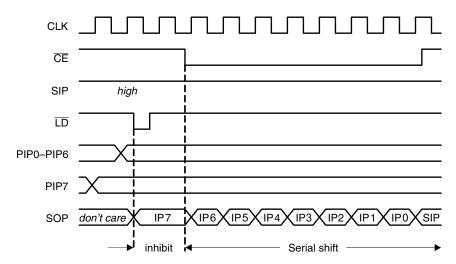


Figure 17. Interface Timing for Parallel-Load and Serial-Shift Operation of the Shift Register

Cascading for High Channel Count Input Modules

Designing high-channel count modules require cascading multiple SN65HVS885 devices. Simply connect the serial output (SOP) of a leading device with the serial input (SIP) of a following device without changing the processor interface.

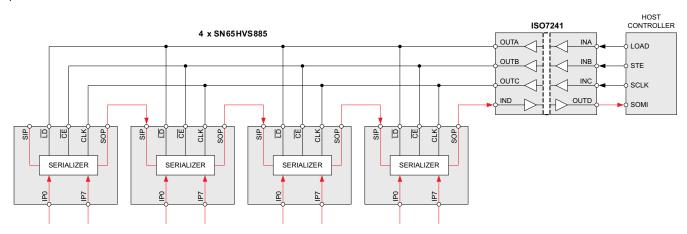


Figure 18. Cascading Four SN65HVS885 for a 32-Channel Input Module

TEXAS INSTRUMENTS

Typical Digital Input Module Application

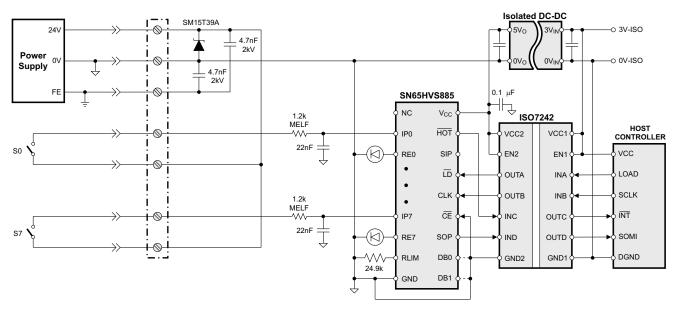


Figure 19. Typical Digital Input Module Application



PACKAGE OPTION ADDENDUM

5-Feb-2009

PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins I	Package Qty	e Eco Plan ⁽²⁾	Lead/Ball Finish	MSL Peak Temp ⁽³⁾
SN65HVS885PWP	ACTIVE	HTSSOP	PWP	28	50	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
SN65HVS885PWPR	ACTIVE	HTSSOP	PWP	28	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

3-Feb-2009

TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device		Package Drawing			Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN65HVS885PWPR	HTSSOP	PWP	28	2000	330.0	16.4	6.9	10.2	1.8	12.0	16.0	Q1





*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN65HVS885PWPR	HTSSOP	PWP	28	2000	346.0	346.0	33.0

PWP (R-PDSO-G**)

PowerPAD™ PLASTIC SMALL-OUTLINE PACKAGE

20 PIN SHOWN



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusions. Mold flash and protrusion shall not exceed 0.15 per side.
- D. This package is designed to be soldered to a thermal pad on the board. Refer to Technical Brief, PowerPad Thermally Enhanced Package, Texas Instruments Literature No. SLMA002 for information regarding recommended board layout. This document is available at www.ti.com www.ti.com.
- E. Falls within JEDEC MO-153

PowerPAD is a trademark of Texas Instruments.



THERMAL PAD MECHANICAL DATA



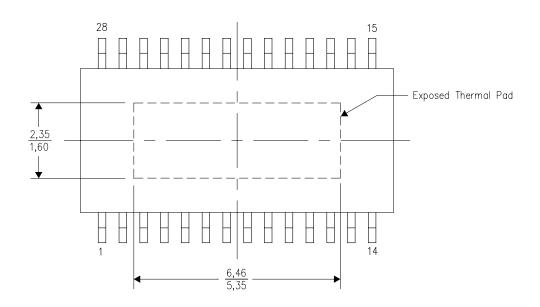
PWP (R-PDSO-G28)

THERMAL INFORMATION

This PowerPAD $^{\mathbf{M}}$ package incorporates an exposed thermal pad that is designed to be attached to a printed circuit board (PCB). The thermal pad must be soldered directly to the PCB. After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For additional information on the PowerPAD package and how to take advantage of its heat dissipating abilities, refer to Technical Brief, PowerPAD Thermally Enhanced Package, Texas Instruments Literature No. SLMA002 and Application Brief, PowerPAD Made Easy, Texas Instruments Literature No. SLMA004. Both documents are available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.

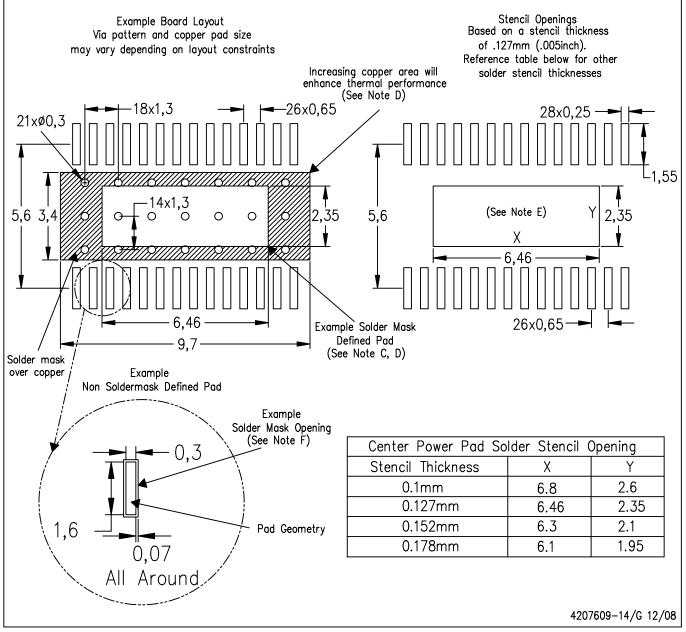


Top View

NOTE: All linear dimensions are in millimeters

Exposed Thermal Pad Dimensions

PWP (R-PDSO-G28) PowerPAD™



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Customers should place a note on the circuit board fabrication drawing not to alter the center solder mask defined pad.
- D. This package is designed to be soldered to a thermal pad on the board. Refer to Technical Brief, PowerPad Thermally Enhanced Package, Texas Instruments Literature No. SLMA002, SLMA004, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com www.ti.com. Publication IPC-7351 is recommended for alternate designs.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Example stencil design based on a 50% volumetric metal load solder paste. Refer to IPC-7525 for other stencil recommendations.
- F. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.

 PowerPAD is a trademark of Texas Instruments.



IMPORTANT NOTICE

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, modifications, enhancements, improvements, and other changes to its products and services at any time and to discontinue any product or service without notice. Customers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All products are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its hardware products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by government requirements, testing of all parameters of each product is not necessarily performed.

TI assumes no liability for applications assistance or customer product design. Customers are responsible for their products and applications using TI components. To minimize the risks associated with customer products and applications, customers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any TI patent right, copyright, mask work right, or other TI intellectual property right relating to any combination, machine, or process in which TI products or services are used. Information published by TI regarding third-party products or services does not constitute a license from TI to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of TI information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. Reproduction of this information with alteration is an unfair and deceptive business practice. TI is not responsible or liable for such altered documentation. Information of third parties may be subject to additional restrictions

Resale of TI products or services with statements different from or beyond the parameters stated by TI for that product or service voids all express and any implied warranties for the associated TI product or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

TI products are not authorized for use in safety-critical applications (such as life support) where a failure of the TI product would reasonably be expected to cause severe personal injury or death, unless officers of the parties have executed an agreement specifically governing such use. Buyers represent that they have all necessary expertise in the safety and regulatory ramifications of their applications, and acknowledge and agree that they are solely responsible for all legal, regulatory and safety-related requirements concerning their products and any use of TI products in such safety-critical applications, notwithstanding any applications-related information or support that may be provided by TI. Further, Buyers must fully indemnify TI and its representatives against any damages arising out of the use of TI products in such safety-critical applications.

TI products are neither designed nor intended for use in military/aerospace applications or environments unless the TI products are specifically designated by TI as military-grade or "enhanced plastic." Only products designated by TI as military-grade meet military specifications. Buyers acknowledge and agree that any such use of TI products which TI has not designated as military-grade is solely at the Buyer's risk, and that they are solely responsible for compliance with all legal and regulatory requirements in connection with such use.

TI products are neither designed nor intended for use in automotive applications or environments unless the specific TI products are designated by TI as compliant with ISO/TS 16949 requirements. Buyers acknowledge and agree that, if they use any non-designated products in automotive applications, TI will not be responsible for any failure to meet such requirements.

Following are URLs where you can obtain information on other Texas Instruments products and application solutions:

Applications Products Amplifiers amplifier.ti.com Audio www.ti.com/audio Data Converters Automotive www.ti.com/automotive dataconverter.ti.com DLP® Products Broadband www.dlp.com www.ti.com/broadband DSP Digital Control dsp.ti.com www.ti.com/digitalcontrol Clocks and Timers www.ti.com/clocks Medical www.ti.com/medical Military Interface www.ti.com/military interface.ti.com Optical Networking Logic logic.ti.com www.ti.com/opticalnetwork Power Mgmt power.ti.com Security www.ti.com/security Telephony Microcontrollers microcontroller.ti.com www.ti.com/telephony Video & Imaging www.ti-rfid.com www.ti.com/video RF/IF and ZigBee® Solutions www.ti.com/lprf Wireless www.ti.com/wireless

> Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2009, Texas Instruments Incorporated